Power Measurement System for 1 mW at 1 GHz

Fred R. Clague

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ABSTRACT

An automated measurement system designed to measure power accurately at the level of 1 mW and at the frequency of 1 GHz is described. The system consists of commercial IEEE Std-488 bus-controlled instruments, a computer controller, and software. The results of a series of measurements are output to the computer display and, optionally, to a printer. The results are the mean of the measurement series and an estimate of the systematic and random uncertainty. The total estimated uncertainty for the average of six consecutive measurements of a nominal 1 mW, 1 GHz source is typically less than 1 percent. The system can measure any power from 0.1 to 10 mW at any microwave frequency by making appropriate changes to the software and possibly, the hardware.

Key words: automated measurement; microwave; microwave power measurement; power; power measurement; power measurement system.

POWER MEASUREMENT SYSTEM FOR 1 mW at 1 GHz

Fred R. Clague

National Institute of Standards and Technology Boulder, Colorado 80303

1. INTRODUCTION

This system is especially designed to accurately measure microwave power at the level of 1 mW and the frequency of 1 GHz. Specifically, it supports the calibration of the Wavetek $8502A^1$ pulse power meter, which has a 1 mW, 1 GHz calibrator output port. The manufacturer's specification on the power level of that output is ± 1.5 percent. Use of the system is not restricted to this specific application; relatively simple modifications to the software would make it possible to measure other power levels and frequencies.

The microwave power measurement method is based on the dc substitution technique. The system is implemented using a commercial version of the NIST-developed Type IV microwave power meter, a commercial coaxial thermistor mount, a digital voltmeter, and a dedicated computer controller. The Type IV power meter is not direct reading; the substituted dc power is calculated using readings obtained from the digital voltmeter. The computer controls the measurement process, calculates the results, and prints them out. The measurement results include an estimate of uncertainty for each data set. The automation also allows the implementation of a procedure that adequately corrects for thermistor mount drift caused by external temperature changes. The system is packaged in a combination operating/shipping case.

¹ Certain commercial instruments and software products are identified in this document in order to adequately specify the instrument supported and the measurement system. Such identification does not imply recommendation or endorsement by NIST nor does it imply that the identified items are necessarily the best available for the purpose.

2. OPERATION

2.1 Initial Steps

Before turning on the Type IV power meter be certain that the thermistor mount is connected to it. The output of the Wavetek 8502A calibrator is found to be more stable after a 2 hour warmup, rather than the 30 minutes specified by the manual. If possible, the 2 hour warmup period is recommended for both the 8502A and the power measurement system. It is also recommended that the thermistor mount be attached to the calibrator output for at least 30 minutes before making the measurement. This will minimize the temperature drift of the mount, improving the measurement accuracy.

Before turning on the computer, load the disk marked "System and Program" in the drive, then turn on the power. The operating system will be automatically loaded. The computer screen will display the time and the several soft-key options: SET CLOCK, LOAD PROGRAM, and EXIT. (The soft keys, or function keys, are the set of eight dark grey keys along the top of the keyboard labeled F1 through F8.) Set the time if needed, and then press the LOAD PROGRAM soft key. The measurement program will be loaded and run.

2.2 Measurement

The first screen displayed by the program is shown in figure 2.1. To see instructions on how to operate the 8502A (to turn the calibrator output on and off), press F1. To enter the serial number of the 8502A being measured, press F2; the serial number will then be printed with the measurement result. To change the number of repeated measurements to be averaged in a set (at least 6 to 10 is recommended), press F3. To begin the measurement set, press F4. To exit the program, press F5.

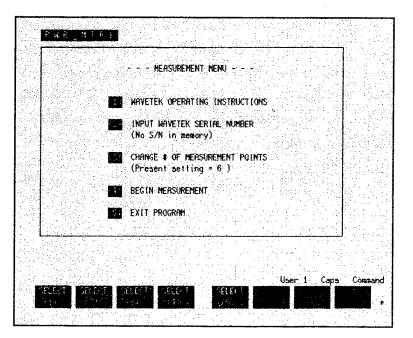


Figure 2.1. Screen display of the measurement menu.

Figure 2.2 shows the screen that appears when the first item is selected from the Measurement Menu. It gives brief instructions for manually controlling the 8502A calibrator output based on information given in the instrument's operating manual. The four numbered steps shown on the screen should be carried out before proceeding with the measurement.

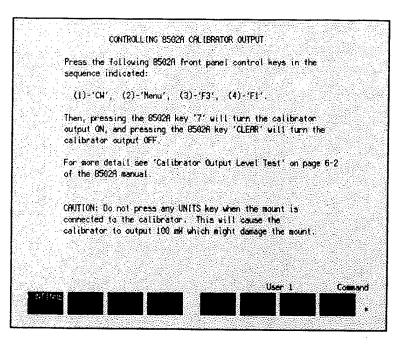


Figure 2.2. Screen display of operating instructions for the calibrator output.

Figure 2.3 shows the screen that appears when F4 is pressed to start the measurement. Just before the message TURN RF ON (PRESS

8502A KEY '7') is displayed, the computer will beep once. At that point press key 7 on the 8502A to turn the rf on and wait for a pair of beeps from the computer. The message will change to TURN RF OFF (PRESS 8502A 'CLEAR'). After pressing the CLEAR key, wait until a single beep sounds again, before pressing key 7 to begin the next measurement in the set. This sequence will be automatically repeated until all the measurements making up the set have been made.

		s/n 2106A20054 Tek Model 8502A,	S/N 1813641		17:04:20	16 Aug 1990
	POWER	PUR- 1. GmW	¥1	Delta V	VI Drift (uV/s)	Ref. Offset (aV)
				*		
19. Star (* 19						

Figure 2.3. Screen display while the measurement is made.

When the desired number of measurements is complete, the final screen that is displayed is shown in figure 2.4.

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					16 Aug 1990
				11 Dec 14	Ref. Offset
					(a.V)
					-7.348
					-7.348
					~7.347
					-7.347
1.005678	+00.568	2.296842	-43,751		-7.345
1.005731	+00.573	2.296804	43.754	-3.1	-7.345
avg pur	AVG-1. Cantol	MAX DE	V STD	DEV SYS U	NC TOT UNC
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Figure 2.4. Screen display of the measurement results.

The upper part of the display summarizes each measurement in the set as explained in table 2.1 below.

Table	e 2.1. Explanation of the upper part of the measurement screen
Column Heading	Explanation
NO.	Number of the power measurement.
POWER	Result of the power measurement in milliwatts.
PWR - 1 mW	Percent deviation of the measured power from 1 milliwatt.
V1	Power meter voltage with the rf off (see section 3.1).
Delta V	Change that occurs in the power meter voltage when the rf is turned on.
V1 Drift	Drift of V_1 in $\mu V/s$ that occurred from the beginning of the measurement until it was complete. Note that if the drift is greater than 10 $\mu V/s$ the measurement should be repeated after waiting a period of time for the mount temperature to further stabilize.
Ref. Offset	The compensation element channel is used as the voltage reference; this column shows the voltage difference between the measurement thermistor channel and the compensation thermistor channel when the rf is off.

The final results are displayed on the screen below the horizontal dashed line. The explanation of each column is given in the following table.

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Table	2.2. Explanation of the results section of the measurement screen
Column Heading	Explanation
AVG PWR	Average power in milliwatts computed from the measured data set.
AVG - 1mW	Percent deviation of the average power level from 1 milliwatt.
MAX DEV	The maximum positive and negative deviations from 1 milliwatt.
STD DEV	The standard deviation of the individual measurements.
SYS UNC	The total calculated systematic uncertainty in the measurement.
TOT UNC	Total uncertainty; the systematic uncertainty plus three times the standard deviation of the mean.

3. SYSTEM DESCRIPTION

3.1 Theory of Operation

The NIST Type IV power meter is not a direct reading instrument. An external precision dc voltmeter must be connected to the power meter, and the power is calculated from the voltmeter readings. The power, P, is given by

$$P = \frac{1}{R_0} \left(V_1^2 - V_2^2 \right), \tag{3.1}$$

where V_1 is the output voltage without rf power, V_2 is the voltage with rf power, and R_0 is the operating resistance of the mount. Note that the so-called "bolometric power" is simply the change of the mount dc bias power as rf power is applied and removed.

It can be seen from eq (3.1) above that, as the rf power becomes small, V_2 approaches V_1 . Because of the uncertainty "magnification" that occurs in the computed difference of two nearly equal numbers, the power measurement uncertainty becomes very large as the power decreases. The solution to this problem is to measure the difference between V_1 and V_2 directly. This requires a reference voltage generator (RVG) which is set nominally equal to V_1 and, in effect, stores V_1 .

When an RVG is used, the expression for calculating power from measured voltages becomes,

$$P = \frac{1}{R_0} \left(2V_1 - \Delta V \right) \Delta V, \qquad (3.2)$$

where R_0 and V_1 were previously defined, and ΔV is the change in the power meter voltage when rf is applied. In providing for a first-order correction of mount drift, the value of V_1 and ΔV are estimated by assuming linear drift and measuring several other voltages while the rf is off, as shown in figure 3.1.

The diagram in figure 3.1 depicts the outputs of the power meter and RVG as a function of time while the rf is cycled on and off. The measurement sequence of five voltage and time readings used to calculate the power and correct for the mount drift is also shown. Note that the reference voltage generator is not set equal to V_1 , nor is it constant with time. This is because it is convenient to use the compensation element of the mount, biased by

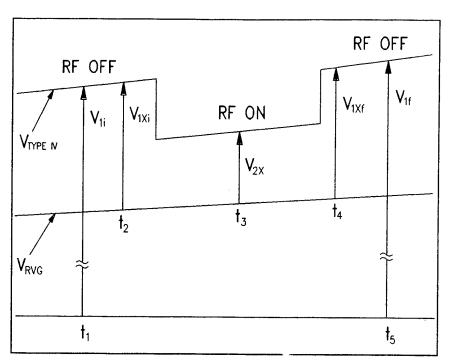


Figure 3.1. Measured power meter voltages vs time.

the second power meter channel, as the reference voltage generator. Thus the RVG does drift during the measurement, but this change is also corrected, to first order, by the measurement series.

In terms of the measured voltages, the values to be used in eq (3.2) are given by,

$$V_{1} = V_{1i} + \left(\frac{t_{3} - t_{1}}{t_{5} - t_{1}}\right) \left(V_{1f} - V_{1i}\right)$$
(3.3)

and,

$$\Delta V = V_{2x} - \left[V_{1xi} + \left(\frac{t_3 - t_2}{t_4 - t_2} \right) \left(V_{1xj} - V_{1xi} \right) \right].$$
(3.4)

3.2 Hardware

The system block diagram is shown in figure 3.2. The input switching to the digital voltmeter (DVM) is done with the multiplexer internal to the DVM. The dual power meter also has an IEEE Std-488 bus interface with controlled output switching, but it is not used in this application. The specifications for the instruments are given in appendix A.

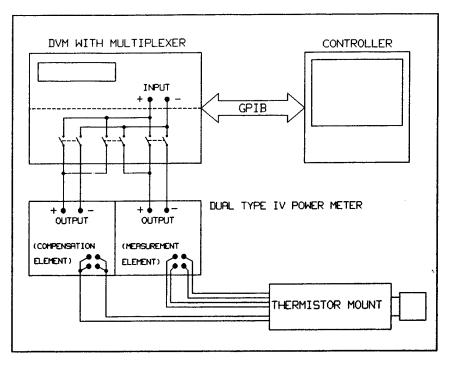


Figure 3.2. System block diagram.

3.3 Software

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A software listing is included as appendix B. Comments at the beginning of the code define the variables (and their location) that one might want to change for other applications such as a different power level or a new mount calibration factor.

4. ERROR ANALYSIS

4.1 Systematic Error Components

The factors contributing to the total systematic uncertainty are:

- 1. Uncertainty in the dc voltage measurements.
- 2. Uncertainty in the thermistor mount effective efficiency calibration.
- 3. Mismatch uncertainty due to the source (8502A calibrator output) reflection coefficient and the thermistor mount reflection coefficient.
- 4. The "dual element substitution error" associated with the coaxial thermistor mount.
- 5. Type IV power meter uncertainty. There are four sources of possible error internal to the power meter. They are, the reference resistors, the operational amplifier open loop gain, input offset voltage, and input bias current. The Type IV error analysis [1] indicates that all of them are negligible compared to the four factors listed above.

The first four of these items will be considered individually in the following sections.

4.1.1 Voltmeter Uncertainty

The effect of uncertainty in the individual voltmeter readings can be determined by taking the total differential of the expression for power, eq (3.2),

$$dP = \frac{2}{R_0} \left[\Delta V \, dV_1 + (V_1 - \Delta V) \, d\Delta V \right], \qquad (4.1)$$

where, in terms of the measured parameters,

$$dV_1 = (1 + T_{1f}) \,\delta V_{1i} + T_{1f} \,\delta V_{1f}, \tag{4.2}$$

$$d\Delta V = \delta V_{2x} + (1 + T_{2f}) \, \delta V_{1xi} + T_{2f} \, \delta V_{1xf}, \qquad (4.3)$$

$$T_{1f} = \frac{t_3 - t_1}{t_5 - t_1}, \tag{4.4}$$

and,

$$T_{2f} = \frac{t_3 - t_2}{t_4 - t_2}.$$
(4.5)

The quantities δV_{1i} , δV_{1f} , δV_{1Xi} , δV_{1Xf} , and δV_{2X} , are the uncertainties in the measured values of V_{1i} , V_{1f} , V_{1Xi} , V_{1Xf} , and V_{2X} . These uncertainties in the measured voltages are based on the voltmeter specifications, which are usually given in two parts as a fraction of reading term, α , and a fraction of full scale term, β . The general expression for the voltmeter uncertainty is given by,

$$\delta V = \alpha V_{reading} + \beta V_{fullscale}.$$
(4.6)

Figure 4.1 shows the uncertainty in power measurement as a function of power level near 1 mW, as calculated using the above procedure (in the calculations, the sign of the independent terms are chosen to give the maximum contribution to the total uncertainty) for the voltmeter, power meter, and measurement configuration used in this system.

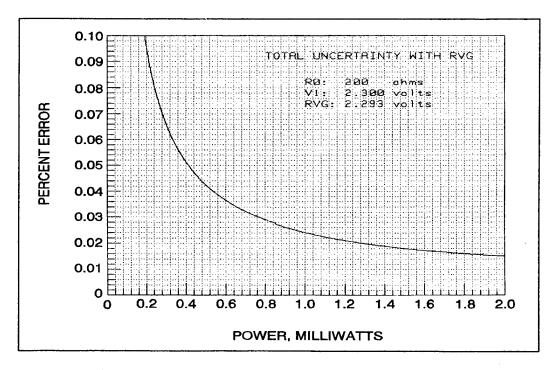


Figure 4.1. Power measurement uncertainty from the DVM.

4.1.2 Uncertainty in Thermistor Mount Effective Efficiency

This is the uncertainty of the NIST thermistor mount calibration. The NIST calibration also gives a value for the mount calibration factor C_f , which is the factor used in this measurement rather than effective efficiency alone, and is defined later in this section. The values listed on the report of calibration will, of course, be constant for any given mount, until the unit is recalibrated. The thermistor mount should be recalibrated periodically.

4.1.3 Mismatch Uncertainty

The net power delivered to a termination by a source is given by,

$$P_{t} = P_{0} \frac{1 - |\Gamma_{t}|^{2}}{|1 - \Gamma_{g}\Gamma_{t}|^{2}}, \qquad (4.7)$$

where P_0 is the power the source would deliver to a nonreflecting termination, Γ_g is the generator reflection coefficient, and Γ_t is the termination reflection coefficient. Ideally, the calibrator should deliver a net power of 1 mW to the power detector being calibrated, but that can only be accomplished if the complex reflection coefficients of the power detector, generator, and calibrating thermistor mount are known, which is generally not the case. Assuming, then, that the calibrator output specification is the power delivered to a nonreflecting load, P_0 , the measured output is given by,

$$P_{0} = \frac{P_{m}}{\eta_{m}} \frac{|1 - \Gamma_{g} \Gamma_{m}|^{2}}{1 - |\Gamma_{m}|^{2}}, \qquad (4.8)$$

where P_m is the bolometrically measured power, η_m is the effective efficiency of the thermistor mount, Γ_g is the generator reflection coefficient, and Γ_m is the thermistor mount reflection coefficient. The denominator of eq (4.8) is the mount calibration factor,

$$C_{f} = \eta_{m} (1 - |\Gamma_{m}|^{2}), \qquad (4.9)$$

so that eq (4.8) becomes,

$$P_0 = \frac{P_m}{C_f} |1 - \Gamma_g \Gamma_m|^2.$$
 (4.10)

The value of Γ_m has been measured during the NIST calibration, but only an upper limit to the magnitude of Γ_g is known (from the source return loss specification). Thus, only the limits to the term involving the reflection coefficients are known,

$$(1 - |\Gamma_{g}| |\Gamma_{m}|)^{2} \leq |1 - \Gamma_{g} \Gamma_{m}|^{2} \leq (1 + |\Gamma_{g}| |\Gamma_{m}|)^{2}, \qquad (4.11)$$

so that P_0 is also only known within the limits,

$$\frac{P_m}{C_f} (1 - |\Gamma_g| |\Gamma_m|)^2 \le P_0 \le \frac{P_m}{C_f} (1 + |\Gamma_g| |\Gamma_m|)^2.$$
(4.12)

This uncertainty in P_0 is the mismatch uncertainty and its relative value is given to first order by,

$$\pm 2 |\Gamma_g| |\Gamma_m|. \tag{4.13}$$

The return loss specification on the calibrator output is greater than 25 dB, which results in a value for $|\Gamma_g|$ of ≤ 0.056 . The value of $|\Gamma_m|$ for the thermistor mount provided is 0.019; together these give a mismatch uncertainty in P_0 of ± 0.21 percent.

4.1.4 Dual Element Error

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The power detector is a dual-element coaxial thermistor mount. Dual-element bolometer units are nonlinear with power level as a result of a dc-rf substitution error that arises because the two elements are not identical [2]. The error is of concern in this measurement because it is being made at 1 mW,

while the NIST calibration of mount efficiency is done at 10 mW. The only way to determine the error magnitude is by direct measurement.

In this case, the method used was to connect the coax mount to one arm of a nominally equal power splitter (for this measurement, a waveguide "magic tee" in WR'90), and a single-element waveguide mount to the other arm. The ratio of the two bolometric powers was determined at 10 mW and again at a randomly selected level between 10 mW and 0.1 mW. The change in the ratios as determined at the two power levels was a measure of the dual-element error.

Figure 4.2 shows results for two identical model waveguide mounts at 9.1 GHz. The increased spread of the data as the power level decreases is typical of bolometric measurements because of the small change in dc power that occurs at low microwave power levels. The -10 dB point on the plot is approximately equal to 1 mW.

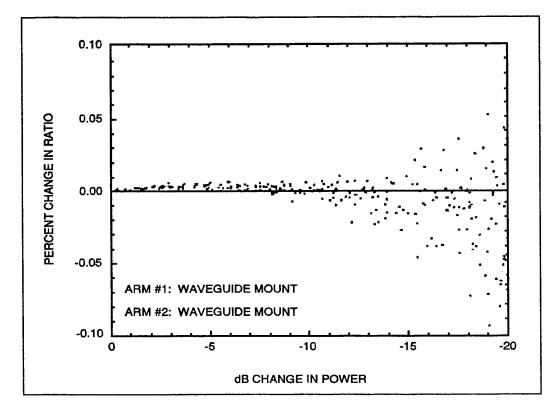


Figure 4.2. Change in the power ratio of 2 waveguide mounts vs power level.

Figure 4.3 is the result for a coax mount compared with one of the waveguide mounts. The change in ratio at the 1 mW level (-10 dB point) is about 0.035 percent. This is the uncertainty that can be expected in the effective efficiency and thus the power measurement at 1 mW, given the calibration is done at 10 mW.

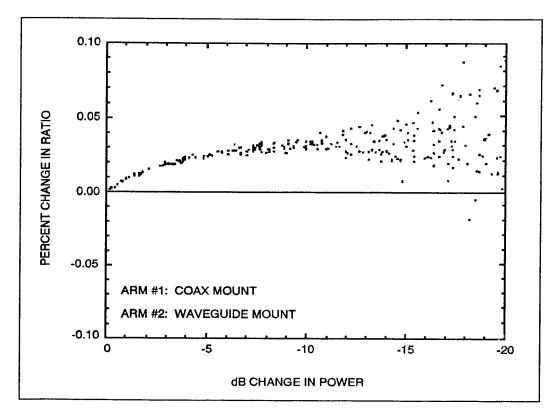


Figure 4.3. Change in the power ratio of a coax mount to a waveguide mount vs power level.

4.2 Random Error

In section 2.2, figure 2.4 shows the measurement screen. The last three columns under the Results section show the standard deviation, the systematic uncertainty, and the total uncertainty of that measurement set. The random contribution to the total uncertainty is chosen to be three times the standard deviation of the mean.

5. REFERENCES

- [1] Larsen, N.T. A new self-balancing dc-substitution rf power meter. IEEE Trans. Instrum.
 Meas. IM-25: 343-347; 1976 December.
- [2] Engen, G.F. A dc-rf substitution error in dual-element bolometer mounts. IEEE Trans. Instrum. Meas. IM-13: 58-64; 1964 June-Sept.

APPENDIX A

Instrument Specifications

- Digital voltmeter: 6½ digit resolution; 3 volt dc range with 0.0025% of reading and 0.0002% of full scale accuracy; 300 mV dc range with 0.0035% of reading and 0.0013% of full scale accuracy; IEEE Std-488 bus; optional integrated reed relay multiplexer. Note: meters with other dc ranges such as 100 mV, 1 volt, and 10 volts are also usable. For instance, a 6½ digit meter with 0.00034% of reading and 0.002% of full scale accuracy on the 100 mV range, 0.00024% of reading and 0.00033% of full scale accuracy on the 1 volt range, and 0.00023% of reading and 0.00016% of full scale accuracy on the 10 volt range, gives results comparable to the 3 volt-300 mV meter.
- 2. Multiplexer: integrated with the DVM (or separate unit); minimum 6 single-pole, single-throw contacts; maximum thermal offset of 3μ V; IEEE Std-488 bus.
- 3. Dual NIST Type IV power meter (or two single units).
- 4. Coaxial thermistor mount: type N male connector; temperature compensation thermistors; dc bias power ≈ 30 mW; maximum $|\Gamma| < 0.025$; NIST calibration at 1 GHz.
- Computer controller: programmable in Hewlett Packard Work Station Basic version 5.13 ("Rocky Mountain Basic"), or TransEra "HT Basic" with IEEE Std-488 capability; IEEE Std-488 bus.

APPENDIX B

Software Listing

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100 105 110 115	File\$="PWRM1" { Started:9001111632/FRC Rev\$="9011210805" [FRC { I NTL author of the subprograms } { Errors, Select_v, and Hp_3457
120 125 130	This program application is the measurement of the 1 mW calibrator output of the Wavetek 8501A peak power meter.
140	NOTES:
150 155	This version measures V1 and delta V with the compensation element used as an RVG. It also calculates the measurement uncertainty.
165 170	Total measurement uncertainty includes: Mount calibration factor uncertainty of ∎0.5973% (For #20054 with Cal Factor of 0.9897)
180 185 190 195	and calculated mismatch uncertainty for the source (Gamma <=0.056) and the mount (Gamma <=0.019) of • 0.21%. The total is 0.8073% plus the DVM and Type IV contribution.
205 210 215	I INSTRUMENTS CONTROLLED: ADDRESS I 1. HP3457A DVM 722 I 2. HP2225A PRINTER 701
230 235	L L DESCRIPTION OF THE MAIN INITIAL VALUE VARIABLES: L
245	The following are in the labeled common named "/Dvm/":
255	** "Dvm_name\$" - the DVM identifier (ie, HP3457A)
265 270	<pre>1 * "PO" - power level in milliwatts. The measurement results are 2 compared with this value. Default setting is 1 mW.</pre>
280 285 290	<pre>* "RO" - mount operating resistance in ohms. Normally 200 ohms for a coax mount and may be either 100 or 200 ohms for a waveguide mount. Default setting is 200 ohms. </pre>
305	t The following are in the labeled common named "/Mount/": 1
315 320	<pre>1 * "Mount\$" - bolometer mount identifier (manufacturer, 1 model, and serial number).</pre>
330 335 340	[1 * "Cf" - NIST measured mount calibration factor. Default setting 1 is 0.9897 for the supplied mount. Value must be changed 2 after mount replacement or recalibration. 2
350 355 360	The following are in the labeled common named "/Errs/":
365 370 375	1 * "Cfu" - total quoted uncertainty of the NIST measured mount 2 calibration factor. Default setting is 0.5973% for the 3 supplied mount. 1
385 390 395	. * "Mmu" - calculated mismatch uncertainty. Default setting is 1 0.21% as indicated in the notes above. 1
	I The following is in the labeled common named "/Wavetek/":
415 420	I "Sn\$" - records the serial number of the Wavetek meter I being measured. It can be input before the measure- I ment from an item on the initial menu.
435 440	
445 450	CHANGING INITIAL VALUE OF VARIABLES
455 460 465 470 475	! * These variables are initally defined in the subprogram "Set_up". To change them, move to the subprogram by executing, "EDIT S". Change the values as needed and "Re-store" the program if the changes are to be permanent.
480 485 490	! [** This variable is initally defined in the subprogram "Hp_3457". ! If a different DVM is used, along with the name, the percent

of reading and the percent of full scale specifications must 495 also be changed in that subprogram. Execute "EDIT hp3457" to 500 505 move to the subprogram. 510 [* * * * * * * * * * * * MAIN PROGRAM * * * * * * * * * * * * * * 515 520 OPTION BASE 1 525 OP LINK BASE 1 COM /Dvm/ PO,RO,A1,A2,A3,A4,A5,B1,B2,B3,B4,B5,R1,R2,R3,R4,R5 COM /Dvm/ Dvm_name\$[40] IDVM ID COM /Errs/ Dp,V1c,V1i,V1f,V1xi,V1xf,V1x,V2x,T1fac,T2fac,Cfu,Mmu 530 535 540 COM /Mount/ Mount\$[40],Cf 545 [Mount ID 550 COM /Wavetek/ Sn\$[7] IFor the serial number REAL P(100,1) 555 For the power measurements [Turn PRT ALL off [Turn off key labels CONTROL 2,1;0 560 KEY LABELS OFF 565 570 CALL Set_up CALL Hp_3457 575 IFor mount & measurement parameters 580 **IGet DVM parameters** 585 CALL Init IHardware initialization 590 Nt=6 IDefault No. of meas 595 LOOP ITo repeat measurement sets 600 CALL Menul(Nt,Quit) 605 IF Quit THEN Quit **ITerminate** 610 CALL Hdr IScreen header REDIM P(Nt,1) 615 IRedimension 620 FOR N=1 TO Nt IMeasurement loop 625 DISP N CALL Meas(N,P1) 630 100 the measurement 635 P(N,1)=P1 IFill array for statistics 640 WAIT 1 lWait before measuring again 645 NEXT N CALL Stats(P(*)) ICalculate the statistics of the run OUTPUT 722;"TRIG AUTO" ILEE DVM continue reading PRINT TABXY(30,1),CHR\$(128);CHR\$(136);" M E A S U R E M E N T C O M P L E T E 650 655 660 CALL Menu2 665 lPost measurement soft keys 670 END LOOP 675 Quit: [Terminate program 680 CLEAR SCREEN 685 END 690 1 695 1* * * * * * * * * * 5 U B PROGRAMS ***** 700 1 705 M: SUB Meas(N,P1) 710 OPTION BASE 1 Sys_prty=VAL(SYSTEM\$("SYSTEM PRIORITY")) IDetermine system priotity Lcl_prty=Sys_prty+1 ISet local priority 1 higher for ON KEY 715 Lcl_prty=Sys_prty+1 [Set local ON KEY O LABEL " ",Lcl_prty GOTO Bail_out 720 725 730 735 COM /Dvm/ P0,R0,A1,A2,A3,A4,A5,B1,B2,B3,B4,B5,R1,R2,R3,R4,R5 740 COM /Dvm/ Dvm_name\$[40] IDVM ID COM /Errs/ Dp,Vlc,Vli,Vlf,Vlxi,Vlxf,Vlx,V2x,Tlfac,T2fac,Cfu,Mmu 745 750 COM /Mount/ Mount\$[40], Cf I Mount ID 755 760 CALL Dvm(V1i,T1i) IV1 before rf turn_on OUTPUT 722; "CHAN 0" 765 IConnect for delta V 770 WAIT .2 775 CALL Dvm(V1xi,T1xi) Initial delta V1 (V1xi) with rf off Vt=V1xi+V1i-SQR(V1i^2-9.E-4*R0)1Calculate threshold for Rf sub 780 785 CALL Rf(1,Vt) [Calls for rf ON and determines when 790 WAIT 1 IFor source to settle 795 CALL Dvm(V2x,T2x) IRead delta V2 (V2x) with rf on 800 CALL Rf(0,Vt) ICalls for rf OFF and determines when Wait again IFinal delta V1 (V1xi) with rf off 805 WAIT 1 810 CALL Dvm(V1xf,T1xf) 815 OUTPUT 722; "CHAN 1" IReconnect for V1 WAIT .2 820 825 CALL Dvm(V1f,T1f) IFinal V1 with rf off 830 Tlfac=(T2x-T1i)/(Tlf-T1i) Vlc=Vli+Tlfac*(Vlf-Vli) 835 [First timing factor 840 IV1 corrections 845 850 T2fac=(T2x-T1xi)/(T1xf-T1xi) ! Second timing factor 855 V1x=V1xi+T2fac*(V1xf-V1xi) IDelta V corrections 860 Dv1=(V1f-V1i)*1.E+6 IChange in V1 865 Dv1_dt=Dv1/(T1f-T1i) IDrift rate of V1 in mV/sec IChange in V2 - (delta V) 870 Dv2=V2x-V1x 875 880 CALL Errors [Calculate errors 885

. ..

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```
890
         P1=1000/R0*(2*V1c-(Dv2))*(Dv2) [Power in mW
895
         P1=P1/Cf
                                        ICal factor correction
900
905
         GOSUB Printout
                                        IPrint results
                                        [Normal exit
910
         SUBEXIT
915 P:
                                        (Printout)
920 Printout:
         IMAGE 30, 5X, Z.60, 5X, S2Z.30, 8X, Z.60, 2X, 30.30, 5X, S20.0, 8X, 20.30
925
         PRINT USING 925; N, P1, 100*(P1-P0)/P0, V1c, Dv2*1.E+3, Dv1_dt, V1x*1.E+3
930
935
         RETURN
                                        Ì
940
945 Bail_out:
                                        LAs it says
         OUTPUT 722; "TRIG AUTO"
950
                                        LOVM continue reading
955
         PRINT
960
         PRINT TABXY(30,1), CHR$(128); CHR$(136); " MEASUREMENT STOPPED
965
         PAUSE
970
         1
975 Exit:
                                        IFinished
980
       SUBEND 1 SUB Meas
       ******
985
990
995 Rf:SUB Rf(On,Vt)
                                        ITurn rf ON/OFF
        IF On THEN
1000
           DISP CHR$(129);" TURN RF ON (PRESS 8502A KEY '7') ";CHR$(128) ITell operator
1005
           BEEP 1000,.01
1010
                                        IGet his attention
           LOOP
                                        IWait for rf to be turned on/off
1015
            CALL Dvm(V,T)
1020
                                        Read DVM
          WAIT 1
EXIT IF V>Vt
1025
1030
                                        ilf rf is turned ON
1035
           END LOOP
1040
         EL SE
1045
           DISP CHR$(129);* TURN RF OFF (PRESS 8502A 'CLEAR') *;CHR$(128) !Tell operator
           BEEP 1000,.01
1050
                                        IGet his attention
          WAIT .2
BEEP 1000,.01
1055
1060
          LOOP
1065
                                        lWait for rf to be turned on/off
            CALL Dvm(V,T)
1070
                                        IRead DVM
          WAIT 1
EXIT IF V<Vt
1075
                                        IIf rf is turned OFF
1080
           END LOOP
1085
         END IF
DISP **
1090
1095
1100
       SUBEND
       [*********
1105
1110
     1
                                        IDVM reading
1115 Dvm:SUB Dvm(V,T)
         SEND 7; UNL LISTEN 22
1120
                                        iGet dvm's attention
1125
         TRIGGER 7
                                        Itrig to read
1130
         ENTER 722;V
                                        IRead DVM
1135
         T=TIMEDATE
                                        IGet the time
1140
       SUBEND
       [*********
1145
1150
1155 Init:SUB Init
                                        [Initialize instruments
1160
1165
         CLEAR 722
                                        IClear 3457
         ULPAR 722; "TERM SCANNER"
OUTPUT 722; "NPLC 10"
OUTPUT 722; "DCV -1"
OUTPUT 722; "TRIG AUTO"
1170
                                        [Connect input to scanner
1175
                                        110 PLC
1180
                                        LAuto Range
1185
                                        ISet up for single readings
1190
1195
         OUTPUT 722; "CHAN 1"
                                        IConnect for V1, floating DVM
1200
         WAIT 1
                                        IMake sure everything is settled
1205
       SUBEND
       [********
1210
1215
1220 H:SUB Hdr
1225
       1
         OPTION BASE 1
1230
1235
         CLEAR SCREEN
1240
         COM /Dvm/ P0,R0,A1,A2,A3,A4,A5,B1,B2,B3,B4,B5,R1,R2,R3,R4,R5
COM /Dvm/ Dvm_name$[40] IDVM ID
COM /Mount/ Mount$[40],Cf IMount ID
1245
1250
1255
1260
         COM /Wavetek/ Sn$[7]
                                        IFor the serial number
1265
         PRINT TABXY(1,1),CHR$(137)&"PWR_MTR1*&CHR$(136)
PRINT TABXY(30,1),CHR$(136);CHR$(129);"MEASUREMENT IN PROGRESS ";CHR$(128)
1270
1275
1280
         t
```

PRINT TABXY(1,3),CHR\$(140);"MOUNT: ";Mount\$;CHR\$(136) PRINT TABXY(59,3),CHR\$(140);TIME\$(TIMEDATE);" ";DATE\$(TIMEDATE);CHR\$(136) PRINT TABXY(1,4),CHR\$(140);"POWER METER: WAVETEK MODEL 8502A, S/N ";Sn\$;CHR\$(136) 1285 1290 1295 1300 1305 DIM A\$[80],B\$[80],C\$[80],D\$[80],Scr\$[80] IString variables to build IMAGE statement 1310 Ima:DATA "#," NO."",4X,"" POWER "",4X,""PWR-""" 1315 Imc:DATA "#,""mw"",6X,"" V1 "",3X,""Delta V"",3X,""V1 Drift"",3X,""Ref. Offset""" RESTORE Ima 1320 READ Scr\$ 1325 IRead as IMAGE statement OUTPUT A\$ USING Scr\$ OUTPUT B\$ USING "#,2D.D";PO 1330 1335 RESTORE Imc 1340 READ Scr\$ 1345 OUTPUT C\$ USING Scr\$ 1350 D\$=A\$&B\$&C\$ 1355 1360 PRINT DS IMAGE "ä Ç",4X,"ä (mw) Ç",4X,"ä (%) Ç",7X,"ä (VOLT) Ç",3X,"ä (mV) Ç",3X,"ä (uV/s) Ç",3X,"ä PRINT USING 1370 1365 1370 (mV) Ç" 1375 1380 1385 SUBEND I Hdr [********* 1390 1395 E:SUB Errors 1400 OPTION BASE 1 COM /DVm/ PO,RO,A1,A2,A3,A4,A5,81,82,B3,B4,85,R1,R2,R3,R4,R5 COM /DVm/ DVm_name\$[40] IDVM ID COM /Errs/ Dp,V1c,V1i,V1f,V1xi,V1xf,V1x,V2x,T1fac,T2fac,Cfu,Mmu 1405 1410 1415 1420 CALL Select_v(V1i,Aali,Bbli,Ssli) CALL Select_v(V1f,Aalf,Bblf,Sslf) 1425 IAa_ - fraction of reading error 1430 CALL Select_v(V1xi,Aa1xi,Bb1xi,Ss1xi) 1435 CALL Select_v(V1xf,Aa1xf,Bb1xf,Ss1xf) CALL Select_v(V2x,Aa2x,Bb2x,Ss2x) IBb_ - fraction of FS error
ISs_ - fullscale reading 1440 1445 1450 1455 GOSUB With_rvg 1460 I GOSUB Servo errors IVery small error - not used for this application 1465 Isub routine removed 1470 Total_error:1 Without RVG. Total=Without+Eerr+Ierr 1475 1480 SUBEXIT 1485 1490 1 1495 With_rvg: 1500 Dvli=Aali*Vli+Bbli*Ssli I Eq's derived 900111/FRC I Delta-V due to initial V1 measmnt I Delta-V due to final V1 measmnt 1510 t Dvlxi=ABS(Aalxi*Vlxi)+Bblxi*Sslxi ! Delta due to initial Vlx measmnt Dvlxf=ABS(Aalxf*Vlxf)+Bblxf*Sslxf ! Delta-V due to final Vlx measmnt 1515 1520 1525 t 1530 Dv2x=ABS(Aa2x*V2x)+Bb2x*Ss2x I Delta-V due to V2x measmont 1535 ł Dv1c=(1+T1fac)*Dv1i+T1fac*Dv1f IError in corrected V1 Dv1x=(1+T2fac)*Dv1xi+T2fac*Dv1xf IError in delta V correction 1540 1545 1550 1 1555 Dpv1=ABS((V2x-V1x)*Dv1c) Dpv1x=ABS((V1c-V2x-V1x)*Dv1x) Dpv2x=ABS((V1c-V2x-V1x)*Dv2x) 1 Delta-power due to V1 measmnt errors 1560 I Delta-power due to Vix 1565 1 Delta-power due to V2x Dp=2*(Dpv1+Dpv1x+Dpv2x)/RO 1570 I Sum (2 & RO left out above) Dp=Dp*1.E+3 1575 1 Dp in mw RETURN 1580 1585 SUBEND 1590 [* * * * * * 1595 1600 1605 Hp3457:SUB Hp_3457 1610 OPTION BASE 1 1615 COM /Dvm/ P0,R0,A1,A2,A3,A4,A5,B1,B2,B3,B4,B5,R1,R2,R3,R4,R5 1620 COM /Dvm/ Dvm_name\$[40] IDVH ID 1625 Dvm_name\$="HP "3457" QUANTITY (HP 3457, 1 yr, 167 ms, 6-1/2 dig) I number of counts, full scale 1630 IFOR DVM: VALUE 1635 Nc: DATA 3.03E6 1 fraction-of-rdg error, range R1, 1 yr 1640 A1: DATA 4.5E-5 I fraction-of-rdg error, range R2, etc. I fraction-of-rdg error, range R3 1645 A2: DATA 3.5E-5 1650 A3: DATA 2.5E-5 fraction-of-rdg error, range R4 fraction-of-rdg error, range R5 1655 A4: DATA 4.0E-5 1660 A5: DATA 5.5E-5 I fraction-of-FS error, counts, range R1, 10 PLC I fraction-of-FS error, counts, range R2 1665 B1: DATA 385. 1670 82: DATA 40. I fraction-of-FS error, counts, range R3 1675 B3: DATA 7.

[fraction-of-FS error, counts, range R4
[fraction-of-FS error, counts, range R5
[lowest range (including overrange), volts 1680 B4: DATA 20. 1685 B5: DATA 7. 0.0303 1690 R1: DATA 1695 R2: DATA 0.303 I next range up 1700 R3: DATA 3.03 i next range up 1705 R4: DATA 30.3 I next range up 1710 R5: DATA 300. I next range up 1715 READ NC, A1, A2, A3, A4, A5, B1, B2, B3, B4, B5, R1, R2, R3, R4, R5 1720 1725 Convert_fs_errs: I Normalize FS count errors to fractional errors 1730 B1=81/Nc 1735 82=82/Nc 1740 B3=B3/Nc 1745 B4=B4/Nc 1750 B5=B5/Nc 1755 SUBEND 1760 1765 Select:SUB Select_v(V,Aa,Bb,Ss) 1770 OPTION BASE 1 COM /Dvm/ PO,RO,A1,A2,A3,A4,A5,B1,B2,B3,B4,B5,R1,R2,R3,R4,R5 COM /Dvm/ Dvm_name\$[40] IDVM ID SELECT ABS(V) I V may be of either polarity CASE <=R1 I Start at lowest range 1775 1780 1785 1790 Start at lowest range
 Fraction of rdg error for V on range R1
 Fraction of FS error for V on range R1
 Fullscale reading for V, range R1
 Range_no number for plot
 Uprange if necessary Aa=A1 1795 Bb=81 1800 1805 Ss=R1 1810 Range=1 CASE <=R2 1815 Aa=A2 1820 8b=82 1825 Ss=R2 ! Etc. for range R2 1830 1835 Range=2 I And again 1640 CASE <=R3 1845 Aa=A3 8b=83 1850 1855 Ss=R3 1860 Range=3 CASE <=R4 Aa=A4 Bb=84 Ss≠R4 1885 Range=4 1890 CASE <=R5 Aa≖A5 1900 Bb≠B5 1905 Ss=R5 1910 Range=5 CASE ĚLSE 1915 REFP 1920 PRINT "Voltage is in excess of 300 volts. Don't be ridiculous." 1925 1930 PAUSE 1935 END SELECT SUBEND 1940 1945 1950 S:SUB Set_up IInitialize mount parameters OPTION BASE 1 1955 OF (JUN BASE 1 COM /Ovm/ PO,RO,A1,A2,A3,A4,A5,B1,82,B3,B4,B5,R1,R2,R3,R4,R5 COM /Ovm/ Dvm_name\$[40] IDVM ID COM /Errs/ Dp,V1c,V1i,V1f,V1xi,V1xf,V1x,V2x,T1fac,T2fac,Cfu,Mmu COM /Mount/ Mount\$[40],Cf Mount\$="HP 8478B, S/N 2106A20054" 1960 1965 1970 1975 1980 Cf=.9897 iMount calibration factor 1985 Cfu=.5973 ICalibration factor uncertainty in % 1990 Mismatch factor uncertainty in & Mount operating resistance in ohms [Comparison power in mw. Note that 1995 Mmu=.21 R0=200 2000 2005 P0=1.0 I the following line limits this setting 2010 Ito a 0.1 mW resolution. 2015 Limit PO to 1 place beyond decimal 2020 PO=DROUND(PO,2) 2025 SUBEND 2030 t 2035 Stats:SUB Stats(REAL P(*)) 2040 OPTION BASE 1 2045 COM /Dvm/ P0,R0,A1,A2,A3,A4,A5,B1,B2,B3,B4,B5,R1,R2,R3,R4,R5 COM /Dvm/ Dvm_name\$[40] IDVM ID COM /Errs/ Dp,Vlc,Vli,Vlf,Vlxi,Vlxf,Vlx,V2x,Tlfac,T2fac,Cfu,Mmu ALLOCATE Dum(SIZE(P,1),1) I Use Dum(*) to preserve P(*) COSUR Sd I Standard dev. of original set 2050 2055 2060 2065 2070 1

Sys_err=Cfu+Mmu+100*Dp/Mean 2075 ISystematic error % (See header notes) Sdm=Sd/SQR(SIZE(P,1)) IStandard Deviation of the mean Tot_unc=Sys_err+300*(Sdm/Mean) ITotal uncertainty % with 3*SD mean 2080 2085 2090 GOSUB Prt (Print results 2095 DEALLOCATE Dum(*) 2100 2105 SUBEXIT 2110 2115 Prt:PRINT "- - - -PRINT "RESULTS:" 2120 2125 2130 DIM A\$[128],8\$[128],C\$[128],O\$[128],Scr\$[128] IString variables to build IMAGE statement 2135 Imd:DATA "#,8X,""AVG PWR "",4X,""AVG-""" 2140 Ime:DATA "#,"mW"",6X,"" MAX DEV "",3X,""STD DEV"",3X,""SYS UNC"",3X,""TOT UNC""" RESTORE Imd 2145 2150 READ Scr\$ IRead as IMAGE statement OUTPUT A\$ USING Scr\$ OUTPUT B\$ USING "#,2D.D";PO 2155 2160 2165 RESTORE Ime 2170 READ Scr\$ 2175 OUTPUT C\$ USING Scr\$ 2180 D\$=A\$&B\$&C\$ 2185 PRINT D\$ 2190 2195 IMAGE 8X,"ä (mw) Ç",4X,"ä (%) Ç",7X,"ä (%) Ç", 3X, "ä (%) Ç", 3X, "ä (%) Ç", 3X, "ä (%) Ç" PRINT USING 2195 2200 IMAGE BX,Z.60,5X,S2Z.30,8X,SZ.30,K,SZ.30,4X,Z.30,5X,Z.30,5X,Z.30 PRINT USING 2205;Mean,100*(Mean-P0)/P0,100*Maxpdv/Mean,",",100*Maxndv/Mean,100*Sd/Mean,Sys_err,Tot_unc 2205 2210 2215 RETURN 2220 1 2225 Sd:1 MAT Dum= P 2230 Sum=SUM(Dum) 2235 1 Sum of the elements in P(*) Mean=Sum/SIZE(P,1) 2240 1 Mean of P(*) 2245 MAT Dum= P-(Mean) 1 Dum(*) contains deviations from mean 2250 Maxpdv=MAX(Dum(*)) 1 Largest positive deviation 2255 Maxndv=MIN(Dum(*)) I Largest negative deviation Maxdv=MAX(ABS(Maxpdv),ABS(Maxndv)) [Largest largest deviat MAT Dum= Dum . Dum l Dum holds squares of deviations 2260 I Largest largest deviation MAT Dum= Dum . Dum IF SIZE(P,1)>1.1 THEN 2265 2270 I Check for single measurement Var=SUM(Dum)/(SIZE(P,1)-1) I Variance 2275 2280 ELSE 2285 Var=SUM(Dum) 2290 END IF Sd=SQR(Var) 2295 I Standard deviation 2300 Max_al=3*Sd I Maximum allowable standard deviation 2305 RETURN 2310 SUBEND 2315 2320 1 2325 Menu2:SUB Menu2 !Post measurement soft keys 2330 OPTION BASE 1 2335 Sys_prty=VAL(SYSTEM\$("SYSTEM PRIORITY")) !Determine system priority 2340 Lcl_prty=Sys_prty+1 ISet local priority 1 higher for ON KEY USER 1 KEYS 2345 list set of soft keys ITurn on soft keys 2350 KEY LABELS ON [Clear keys 2355 FOR N=0 TO 19 ON KEY N LABEL "" GOTO Top IDefault destination 2360 2365 NEXT N ON KEY 1 LABEL " MENU ",LC1_prty GOTO Exit ON KEY 2 LABEL " PRINT ",LC1_prty GOSUB Print 2370 2375 2380 1 2385 Top:LOOP IWait for input 2390 END LOOP 2395 Print: [A]pha dump 2400 KEY LABELS OFF ITurn off soft keys 2405 DUMP ALPHA LAs it says 2410 KEY LABELS ON ITurn keys back on 2415 RETURN 2420 Exit: t 2425 KEY LABELS OFF 2430 SUBEND 2435 1 2440 Menul:SUB Menul(Nt,Quit) 1PRE measurement set up & soft keys 2445 OPTION BASE 1 Sys_prty=VAL(SYSTEM\$("SYSTEM PRIORITY")) [Determine system priority 2450 ISet local priority 1 higher for ON KEY 2455 Lcl_prty=Sys_prty+1 2460 2465 COM /Wavetek/ Sn\$[7] !For the serial number

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M_flag=1 2470 ITo write menu 2475 USER I KEYS list set of soft keys 2480 KEY LABELS ON ITurn on soft keys 2485 FOR N=0 TO 19 IClear keys ON KEY N LABEL "" GOTO TOP 2490 IDefault destination 2495 NEXT N 2500 1 ON KEY 1 LABEL * SELECT ON KEY 2 LABEL * SELECT ON KEY 3 LABEL * SELECT ON KEY 4 LABEL * SELECT (1)",Lcl_prty GOSUB Help (2)",Lcl_prty GOSUB Sn (3)",Lcl_prty GOSUB Change (4)",Lcl_prty GOTO Exit (5)",Lcl_prty GOTO Quit 2505 2510 2515 2520 2525 ON KEY 5 LABEL " SELECT 2530 t 2535 Top:LOOP lWait for input 2540 IF M_flag=1 THEN GOSUB Menu 2545 END LOOP 2550 2555 Menu: CLEAR SCREEN PRINT TABXY(5,2),CHR\$(129);" P W R _ H T R 1 ";CHR\$(128) 2560 CLIP 10,110,24,88 2565 ITo draw a box 2570 FRAME PRINT TABXY(24,5),"- - - MEASUREMENT MENU - - -" PRINT TABXY(20,8),CHR\$(129);"(1)";CHR\$(128);" WAVETEK OPERATING INSTRUCTIONS" PRINT TABXY(20,10),CHR\$(129);"(2)";CHR\$(128);" INPUT WAVETEK SERIAL NUMBER" IF Sn\$="" THEN 2575 2580 2585 2590 PRINT TABXY(25,11), "(No S/N in memory)" 2595 2600 ELSE 2605 PRINT TABXY(25,11), "(S/N "; Sn\$;" in memory)" 2610 END IF PRINT TABXY(20,13),CHR\$(129);"(3)";CHR\$(128);" CHANGE # OF MEASUREMENT POINTS" PRINT TABXY(25,14),"(Present setting =";Nt;") " PRINT TABXY(20,16),CHR\$(129);"(4)";CHR\$(128);" BEGIN MEASUREMENT" PRINT TABXY(20,18),CHR\$(129);"(5)";CHR\$(128);" EXIT PROGRAM" 2615 2620 2625 2630 M_flag=0 RÉTURN 2635 2640 2645 Sn: [Input the WAVETEK serial number ITurn off soft keys 2650 KEY LABELS OFF LINPUT "WAVETEK SERIAL NUMBER ?", Sn\$[1,7] 2655 Sn\$=TRIM\$(Sn\$) 2660 2665 PRINT TABXY(25,11), "(S/N "; Sn\$;" in memory)" 2670 KEY LABELS ON ITurn keys back on 2675 RETURN 2680 Change: IChange # of meas points
ITurn off soft keys 2685 KEY LABELS OFF 2690 INPUT "NUMBER OF MEASUREMENT POINTS ?", Nt 2695 Nt=MIN(Nt,100) 2700 Nt=MAX(Nt,1) 2705 PRINT TABXY(25,14), "(Present setting =";Nt;") " ITurn keys back on 2710 KEY LABELS ON 2715 RETURN 2720 Help: With operation of Wavetek 2725 CALL Help 2730 M_flag=1 2735 RETURN 2740 Quit: ITerminate program 2745 Quit=1 2750 Exit: 1 2755 KEY LABELS OFF 2760 SUBEND 2765 1 2770 Help:SU8 Help 2775 CLEAR SCREEN 2780 **OPTION BASE 1** Sys_prty=VAL(SYSTEM\$("SYSTEM PRIORITY")) 1Determine system priority 2785 2790 Set local priority 1 higher for ON KEY
11st set of soft keys Lcl_prty=Sys_prty+1 2795 USER 1 KEYS 2800 KEY LABELS ON ITurn on soft keys 2805 FOR N=0 TO 19 [Clear keys 2810 ON KEY N LABEL "" GOTO TOD IDefault destination 2815 NEXT N ON KEY 1 LABEL "CONTINUE", Lcl_prty GOTO Exit 2820 2825 **GOSUB** Text IPrint info 2830 1 2835 Top:LOOP IWait for input 2840 END LOOP 2845 2850 Text:PRINT TABXY(22,2), "CONTROLLING 8502A CALIBRATOR OUTPUT" 2855 PRINT TABXY(12,4), "Press the following 8502A front panel control keys in the" 2860 PRINT TABXY(12,5), "sequence indicated:"

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PRINT TABXY(14,7),"(1)-'CW'," PRINT TABXY(25,7),"(2)-'Menu'," PRINT TABXY(38,7),"(3)-'F3'," PRINT TABXY(38,7),"(4)-'F1'." PRINT TABXY(12,9),"Then, pressing the 8502A key '7' will turn the calibrator" PRINT TABXY(12,10),"output 0N, and pressing the 8502A key 'CLEAR' will turn the" PRINT TABXY(12,11),"calibrator output OFF." PRINT TABXY(12,13),"For more detail see 'Calibrator Output Level Test' on page 6-2" PRINT TABXY(12,17),"CAUTION: Do not press any UNITS key when the mount is" PRINT TABXY(12,18),"connected to the calibrator. This will cause the" PRINT TABXY(12,19),"calibrator to output 100 mW which might damage the mount." RETURN 2875 RETURN t 2935 Exit: Ŀ SUBEND

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